

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	58	(simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked) same (fault faults faulty defective defect defects)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/25 13:20
L2	23	(simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked) same (fault faults faulty defective defect defects)	US-PGPUB	OR	ON	2006/03/25 13:28
L3	3	((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects) same (good golden reference)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked) same (fault faults faulty defective defect defects)	US-PGPUB	OR	ON	2006/03/25 13:29
L4	22	((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects) same (good golden reference)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked) same (fault faults faulty defective defect defects)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/25 13:31
L5	21	((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked) same (fault faults faulty defective defect defects) same (good golden reference))	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/25 13:31

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L6	47	((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked) same (fault faults faulty defective defect defects) and (good golden reference)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/25 14:28
L8	1	"878554" and good	US-PGPUB	OR	ON	2006/03/25 13:53
L9	24	((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked) same (fault faults faulty defective defect defects) and ((good golden reference) with (IC integrated circuit semiconductor semi-conductor))	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/25 13:43
L10	1	"878554" and (good adj machine adj (simulate simulates simulating simulation simulated))	US-PGPUB	OR	ON	2006/03/25 14:22
L11	11	(good adj machine adj (simulate simulates simulating simulation simulated))	US-PGPUB	OR	ON	2006/03/25 14:38
L12	16	(good adj machine adj (simulate simulates simulating simulation simulated))	USPAT	OR	ON	2006/03/25 13:55
L13	1	"878554" and (good adj machine adj (simulate simulates simulating simulation simulated))	US-PGPUB	OR	ON	2006/03/25 14:33
L14	47	((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked) same (fault faults faulty defective defect defects) and (good golden reference (fault adj free))	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/25 14:29

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L15	28	((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrack backtraced backtraces backtracing backtrack backtracks backtracking backtracked) same (fault faults faulty defective defect defects) and ((good golden reference (fault adj free)) with (IC integrated circuit semiconductor semi-conductor))	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/25 14:30
L16	4	15 not 9	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/25 14:31
L17	2	((good golden reference (fault adj free)) near (machine circuit IC integrated semiconductor) near (simulate simulates simulating simulation simulated)) and ((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrack backtraced backtraces backtracing backtrack backtracks backtracking backtracked)	US-PGPUB	OR	ON	2006/03/25 14:42
L18	16	((good golden reference (fault adj free)) near (machine circuit IC integrated semiconductor) near (simulate simulates simulating simulation simulated)) and ((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrack backtraced backtraces backtracing backtrack backtracks backtracking backtracked)	USPAT	OR	ON	2006/03/25 14:43

## EAST Search History

L19	2	((good golden reference (fault adj free)) near (machine circuit IC integrated semiconductor) near (simulate simulates simulating simulation simulated)) and ((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked)	USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/25 15:43
L20	17	((good golden reference (fault adj free) (true adj value)) near (machine circuit IC integrated semiconductor (simulate simulates simulating simulation simulated)) near (simulate simulates simulating simulation simulated)) and ((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked)	USPAT	OR	ON	2006/03/25 15:52
L21	17	((good golden reference (fault adj free) ((true good) adj value)) near (machine circuit IC integrated semiconductor (simulate simulates simulating simulation simulated)) near (simulate simulates simulating simulation simulated)) and ((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrace backtraced backtraces backtracing backtrack backtracks backtracking backtracked)	USPAT	OR	ON	2006/03/25 16:08

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L22	2	((good golden reference (fault adj free) ((true good) adj value)) near (machine circuit IC integrated semiconductor (simulate simulates simulating simulation simulated)) near (simulate simulates simulating simulation simulated)) and ((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrack backtraced backtraces backtracing backtrack backtracks backtracking backtracked)	USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/25 16:07
L23	2	((good golden reference (fault adj free) ((true good) adj value)) near (machine circuit IC integrated semiconductor (simulate simulates simulating simulation simulated)) near (simulate simulates simulating simulation simulated)) and ((simulate simulates simulating simulation simulated) same (fault faults faulty defective defect defects)) and ((back adj (trace traced traces tracing track tracks tracking tracked)) backtrack backtraced backtraces backtracing backtrack backtracks backtracking backtracked)	US-PGPUB	OR	ON	2006/03/25 16:18
L24	2	((good golden reference (fault adj free) ((true good) adj value)) near (machine circuit IC integrated semiconductor (simulate simulates simulating simulation simulated)) near (simulate simulates simulating simulation simulated)) with (IC integrated semi-conductor semiconductor)	US-PGPUB	OR	ON	2006/03/25 16:20
L25	15	((good golden reference (fault adj free) ((true good) adj value)) near (machine circuit IC integrated semiconductor (simulate simulates simulating simulation simulated)) near (simulate simulates simulating simulation simulated)) with (IC integrated semi-conductor semiconductor)	USPAT	OR	ON	2006/03/25 16:20

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IEE JNL	IEE Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
IEEE STD	IEEE Standard

## Modify Search

((((good <or> golden <or> reference <or> (fault <near/1> free)) <and> (machine <or>

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